

2026 年 10 月 7 日

株式会社テセック

SEMICON WEST 2026 出展のご案内

2026 年 10 月 13 日～15 日に開催される SEMICON WEST 2026 に出展いたします。
皆様のご来場を心よりお待ちしております。

会 場：Moscone Center | San Francisco, CA

ブース：South Hall #458

SEMICON WEST 公式ウェブサイト：<https://www.semiconwest.org/>



SEMICON® WEST
October 13-15, 2026

TeSEC®
*Driving the Real World Forward
Through Device Handling & Testing*

Semiconductor Handling & Testing

Data Center

- Can large panels be handled precisely?
→ **PLP Handling**
- How are strip devices tested efficiently?
→ **Strip Handling**
- Can fragile packages survive handling?
→ **Low-Stress Handling**
- How is throughput maintained at scale?
→ **High-Throughput**
- Ready for next-gen AI packaging?
→ **Advanced Test Solutions**

Panel Level Package

5170-IH
BGA / WLCSP / PLP
PLP : 300mm x 300mm

Strip

5880-IH
SO / QFN
-55°C ~ +175°C
Strip : 300mm x 100mm

Physical AI

- Precise motion sensing?
→ **MEMS Testing**
- Multi-axis accuracy?
→ **6DoF Measurement**
- Stable across temperature?
→ **Thermal Control**
- Reliable power delivery?
→ **IPM Testing**
- Real-world validation?
→ **High-Voltage/Current Testing**

MEMS

4664-IH (Ultra P)
6DOF
QFN / SO / LGA
-40°C ~ +135°C

IPM Module

5665-UL
6DOF
QFN / SO / LGA
-40°C ~ +135°C

530-IT
2.2kV / 200A
IPM / IPD / IGBT
2 parallel

Automotive

- Can devices ensure functional safety?
→ **Automotive Testing**
- How do systems perform under harsh conditions?
→ **Reliability Testing**
- Can power modules handle real driving loads?
→ **Load Testing**
- How stable is performance across temperature?
→ **Thermal Testing**
- Ready for EV and autonomous driving?
→ **Next-Gen Automotive Testing**

SiC / GaN

431-TT
2.2kV / 200A
Option : 10kV / 1200A
32pin Scanner

Wafer Parallel Test

471-TTL
2kV / 200A
4 parallel
UIS

Renewable Energy

- Stable power from renewables?
→ **Power Device Testing**
- Can efficiency be maintained under load?
→ **Loss / Performance Evaluation**
- How do devices withstand harsh conditions?
→ **Reliability Testing**
- What defines inverter performance?
→ **Switching / Power Evaluation**
- Are systems ready for real operation?
→ **High-Load Testing**

Dynamic Test

3430-SW
1.5kV / 300A
Switching time
tr / Gtr
Short circuit

Avalanche Test

4602-LV
300V / 200A
Programmable coil

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